Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,646	LEE, HEON	
Examiner	Art Unit	
Fric R Chen	1765	

	SEARCHED			
Class	Subclass	Date	Examiner	
	l		<u> </u>	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor search (PALM) (UPDATED)	2/13/2006	EC
EAST (all databases) - see search history printout	2/13/2006	EC
216/2,11-13,33-36,44,52-54,67,79,81, 88-91,96; 264/320; 249/115,118,114.1 (text search only) (UPDATED)	2/13/2006	EC